

ouc	or References Cited	Examiner	
		Joseph Nguye	

Application/Control No. 10/080,832	Reexamination	Applicant(s)/Patent Under Reexamination HARAGUCHI ET AL.		
Examiner	Art Unit			
Joseph Nauven	2815	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date - MM-YYYY	Name	Classification
	Α	US-6522003B1	02-2003	Minami et al	257/758
	В	US-6198128B1	03-2001	Asakura et al	257/337
	С	US-			
	D	US-	_		
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP11-175022	07-1999	Japan	Teronai et al	
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*	* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	υ		
	<b>v</b>		
	w		
	х		

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYYY format are publication dates. Classifications may be US or foreign.